AMENDMENTS TO THE CLAIMS:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

Claims 1-6. (Canceled)

7. (Currently Amended) ~~The method of claim 5, further comprising~~A switching system which includes a plurality of devices formed in a dual active structure, a device controller for controlling the devices, and a main processor, a path management and testing method for the switching system, comprising:

using the device controller to check a valid path and state change for each board, for forming a database using the main processor;

searching the database and confirming a standby path;

performing a path test for an entire interval or a certain interval with respect to the active or standby path, wherein said path test includes:

receiving a parameter value used for the path test,

forming a test path based on the parameter value,

inserting a test pattern data into an input side device,

extracting a test pattern data from an output side device, and

judging an error with respect to the test path interval by comparing an input data and an extraction data; and

performing an interval-based path test when the input data and the extracted data are different and searching for an error interval.

Claims 8-11. (Canceled)

12. (Currently Amended) ~~The method of claim 11,~~ In a switching system of a dual active structure, a standby path test method, comprising:

checking an active path formed in a direction of a matched receiving board provided at a receiving side terminal, checking an active path in the reverse direction of a data transmission direction, and searching an entire active path by checking a switching path of the board connected to the active path;

setting a reverse path of the active path as a standby path; and

performing a path test with respect to the set standby path, wherein said path test includes:

receiving a certain parameter value needed for ~~a~~ the path test[[:]];

forming a switching path based on the set standby path;

inserting a test pattern data from the output side device;

judging whether there is an error in the standby path based on a comparison result with respect to the input data and the extraction data; and

searching an error interval by performing an inter-based path test in the case that the input data and the extracted data are not same.

13. (Previously Presented) The method of claim 12, further comprising repeatedly performing a test by setting a number of repetitions and period.

14. (Original) The method of claim 12, wherein said parameter value indicates a test type, a board for inserting or extracting a test pattern data, a subsystem for mounting the board, a link number in the subsystem, and a pattern data used for the test.

15. (Original) The method of claim 14, wherein said parameter value indicates a test repetition period and repetition number.

Claims 16-20. (Canceled)